

Fig. 1

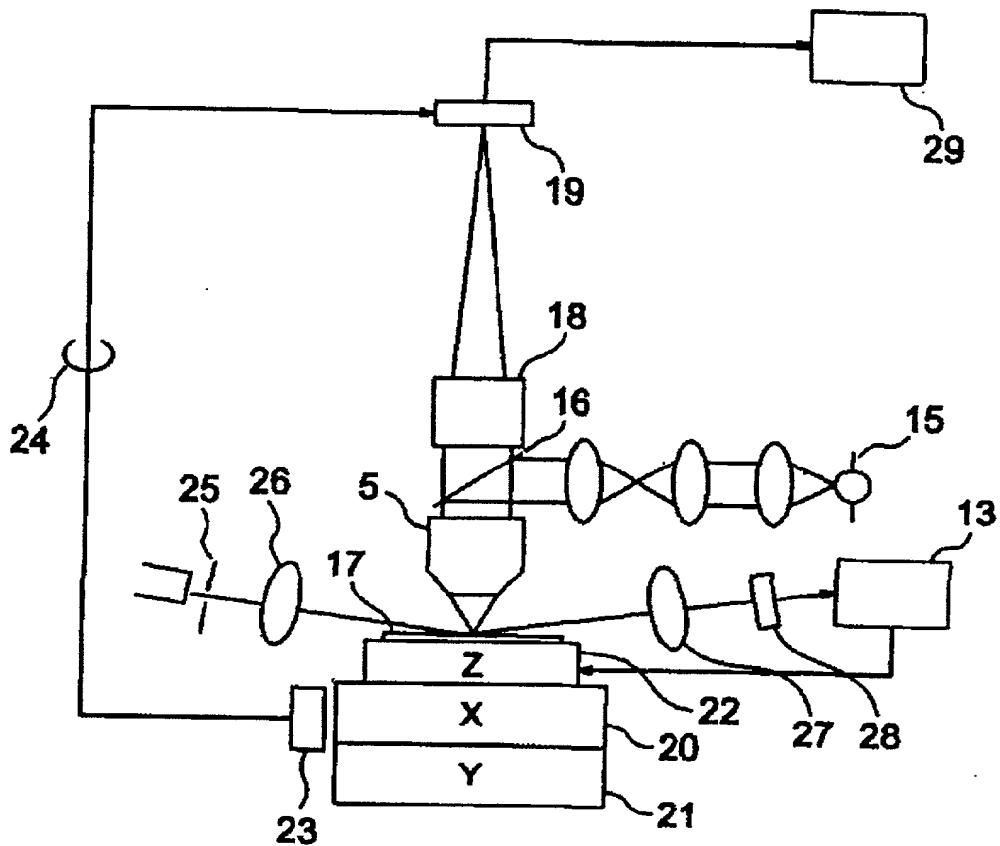


Fig. 2

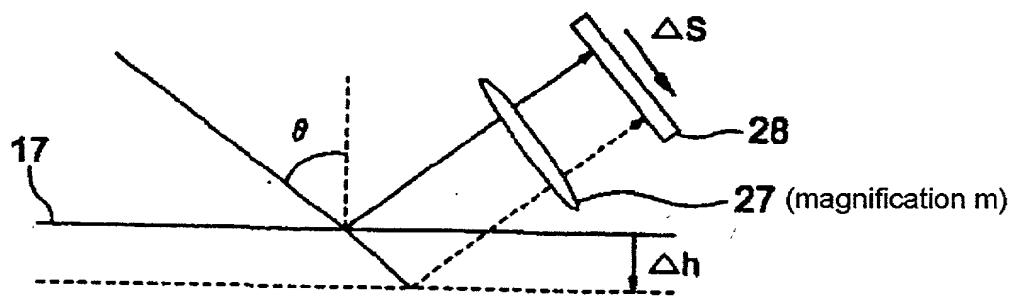


Fig. 3

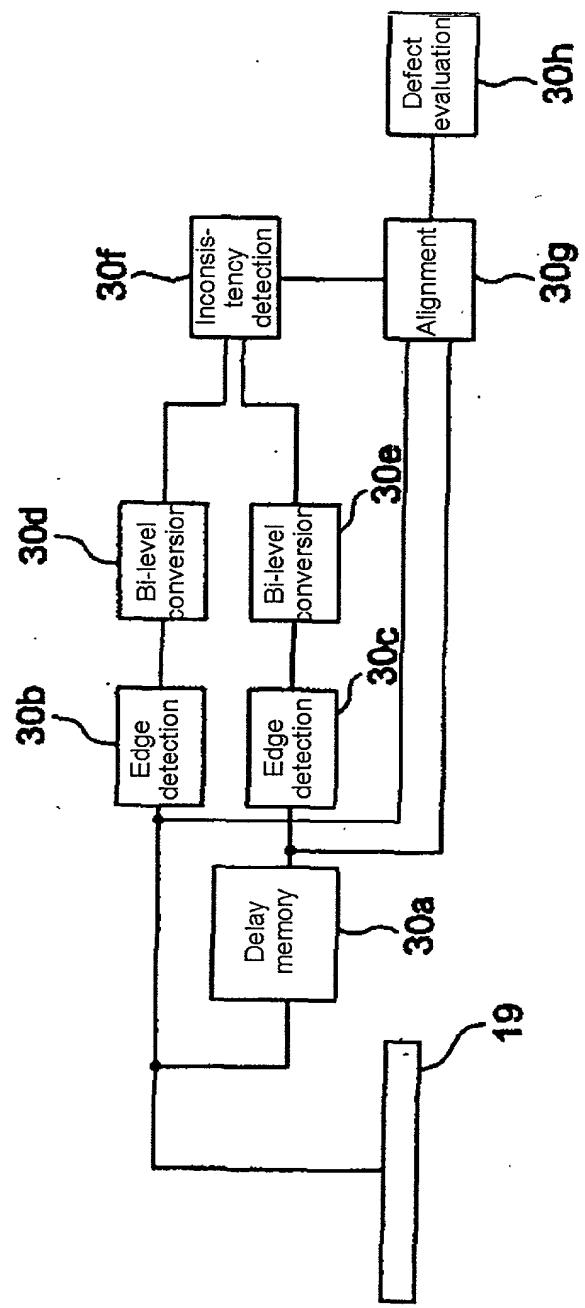


Fig. 4

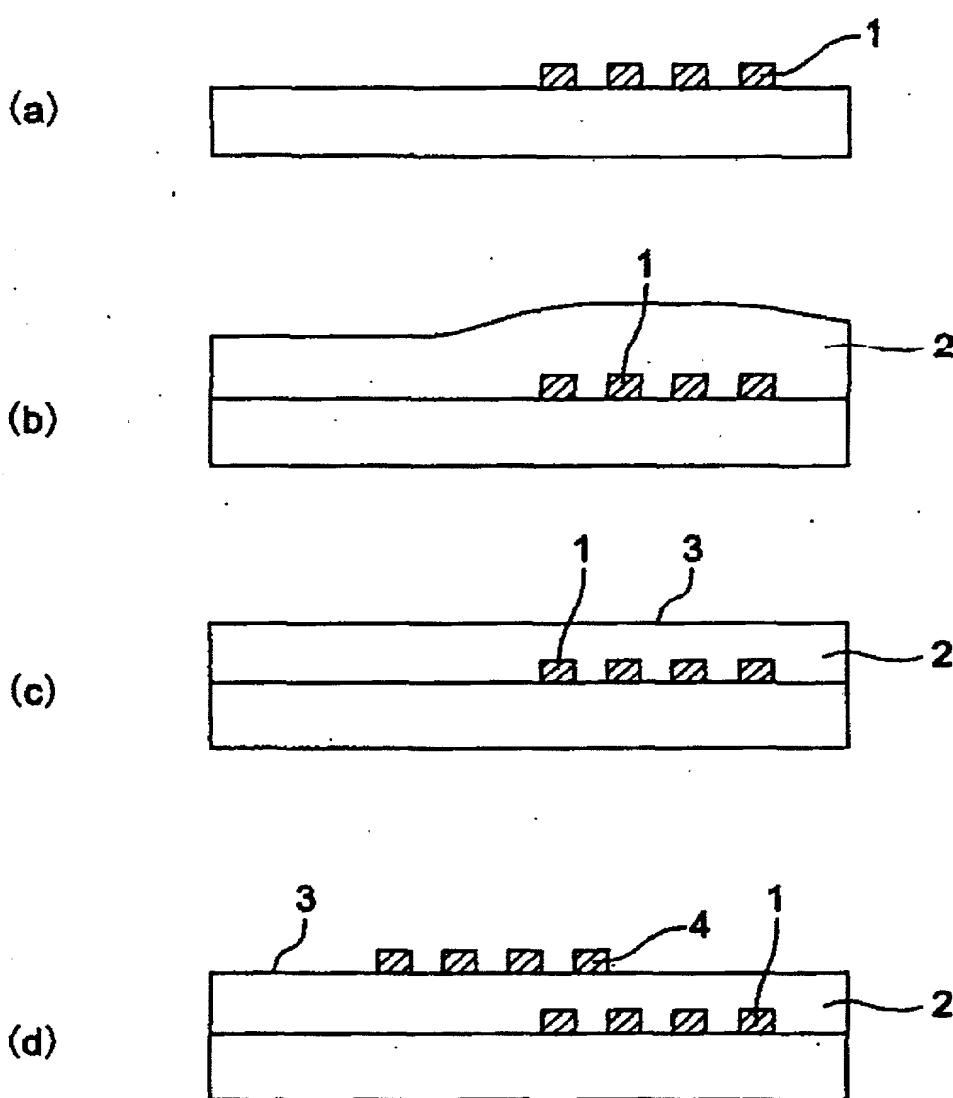
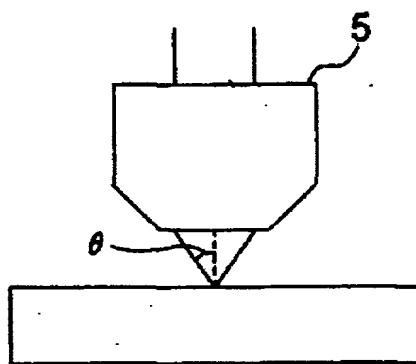


Fig. 5

(a)



(b)

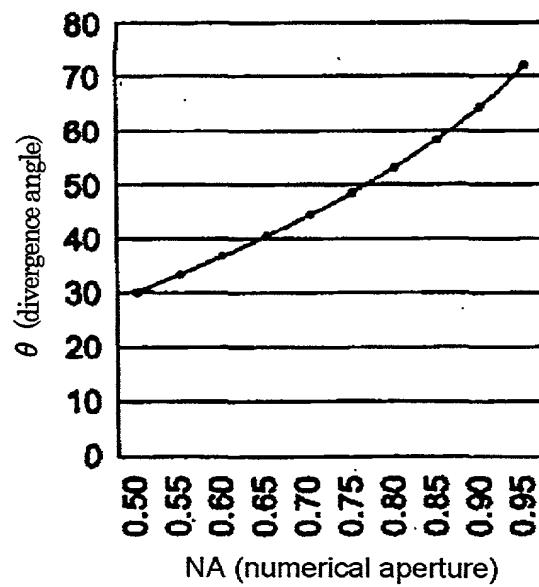
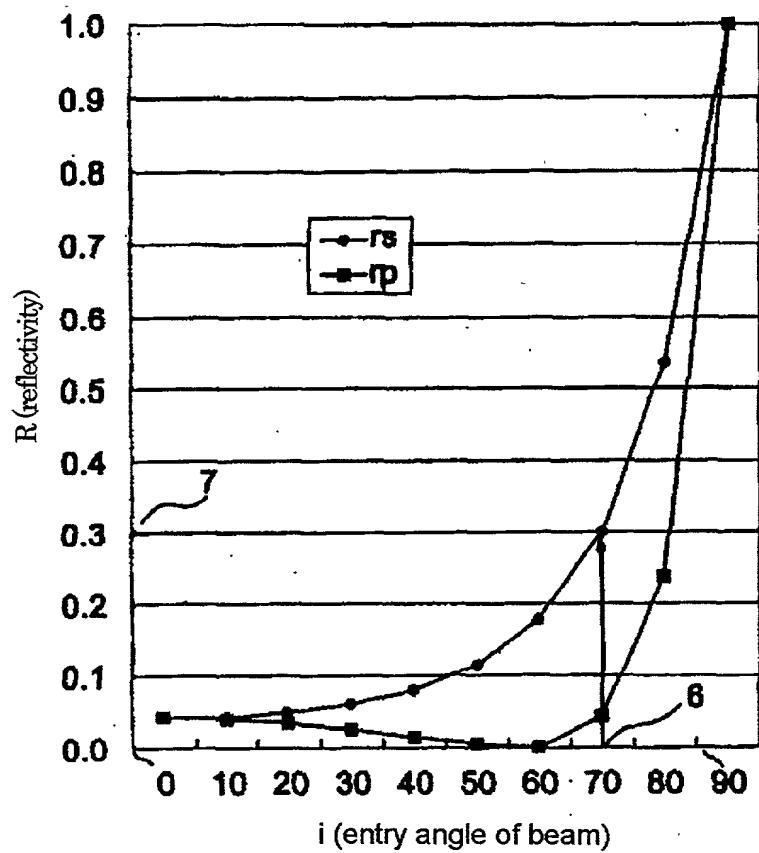


Fig. 6



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Fig. 7

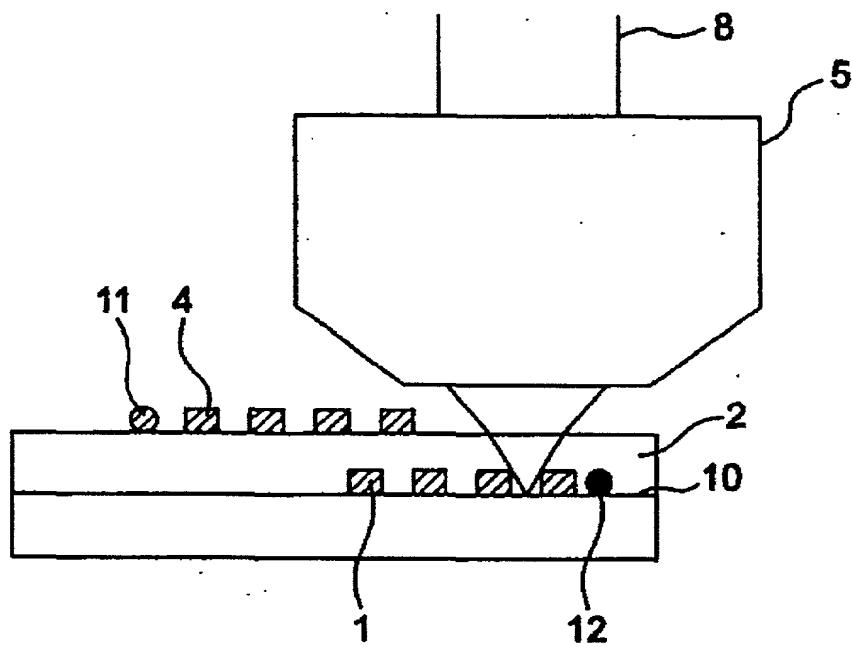


Fig. 8

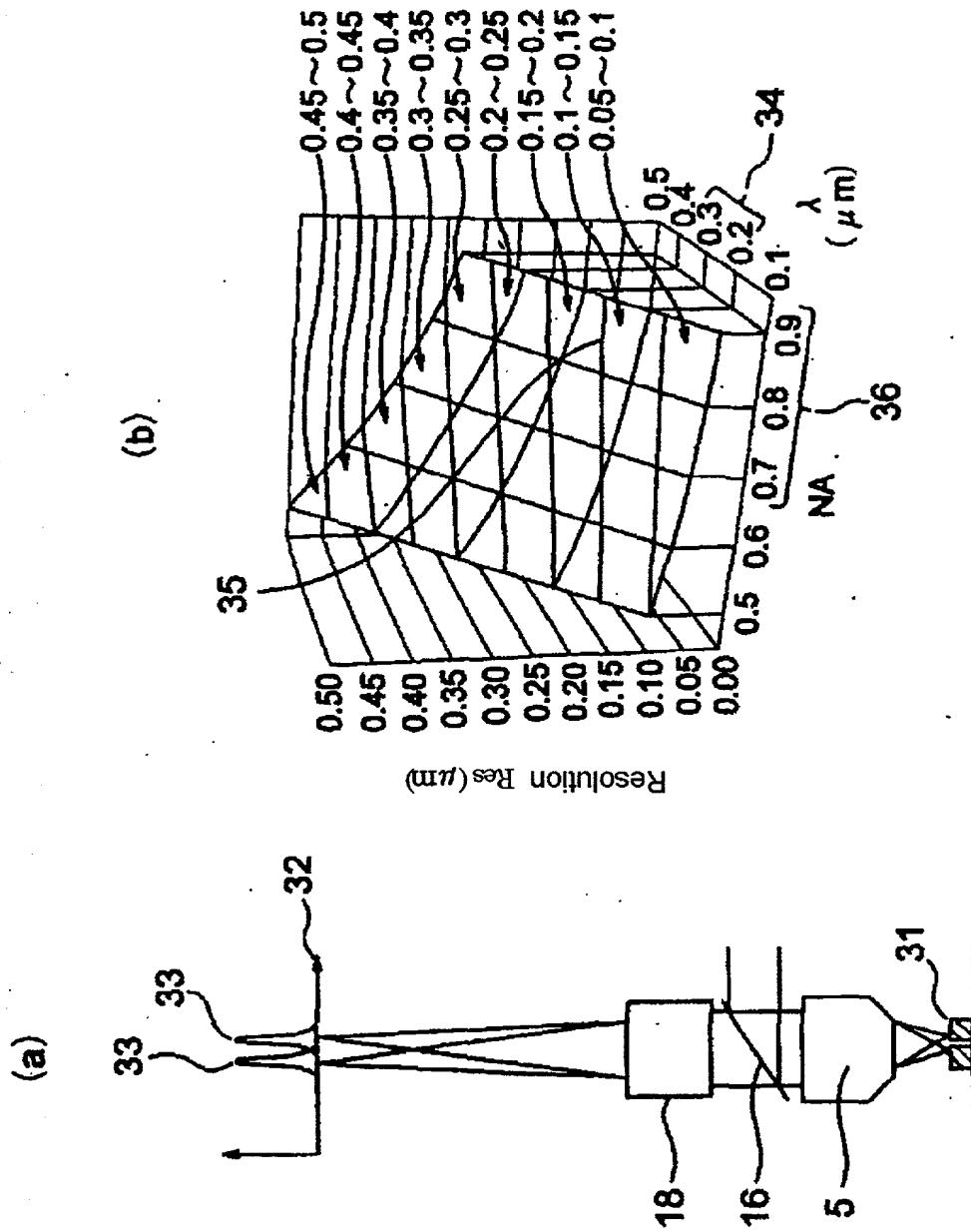


Fig. 9

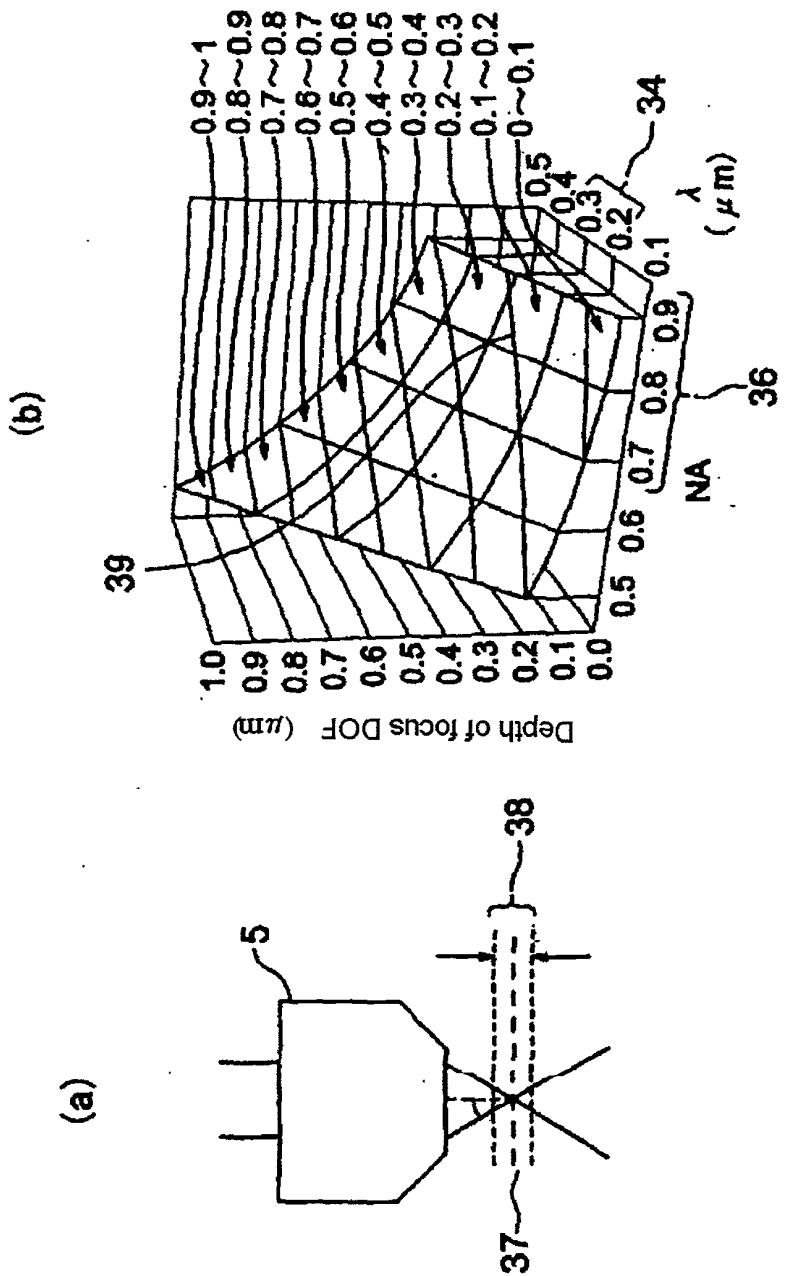


Fig. 10

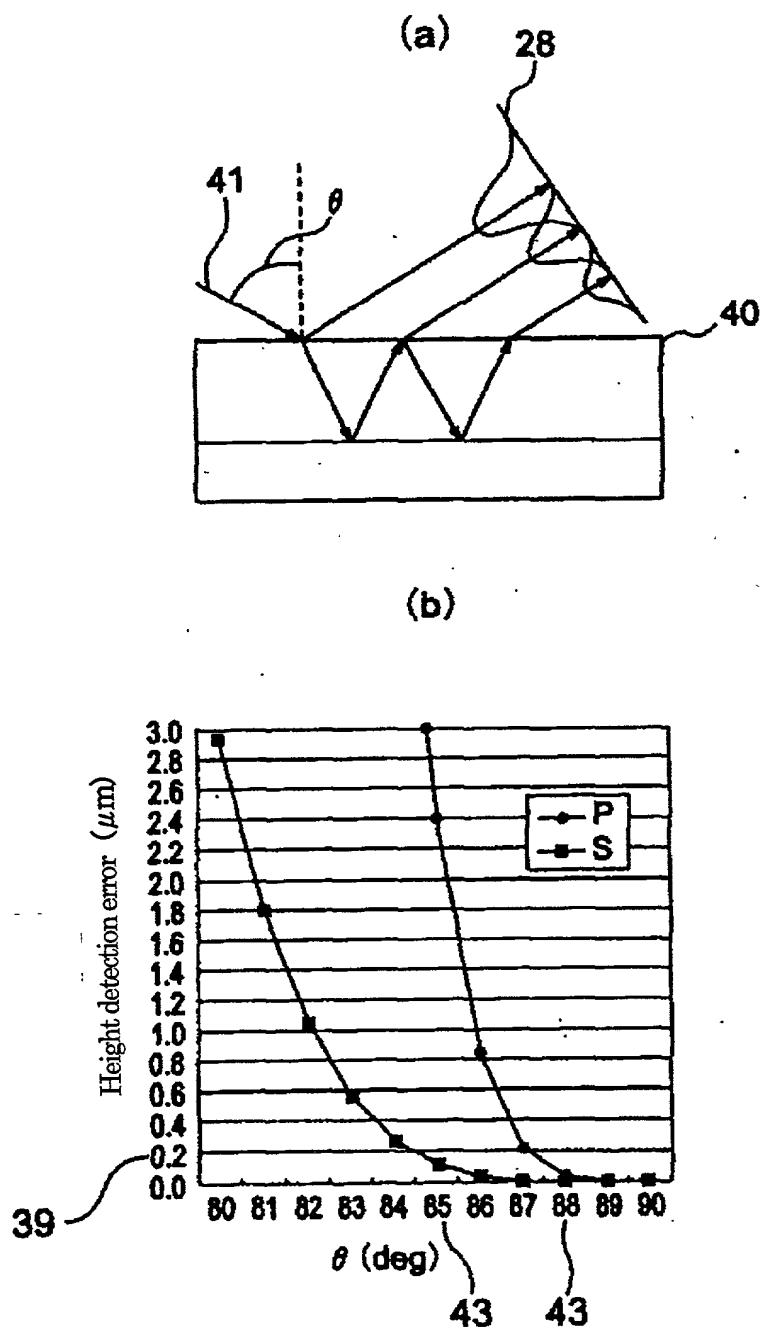


Fig. 11

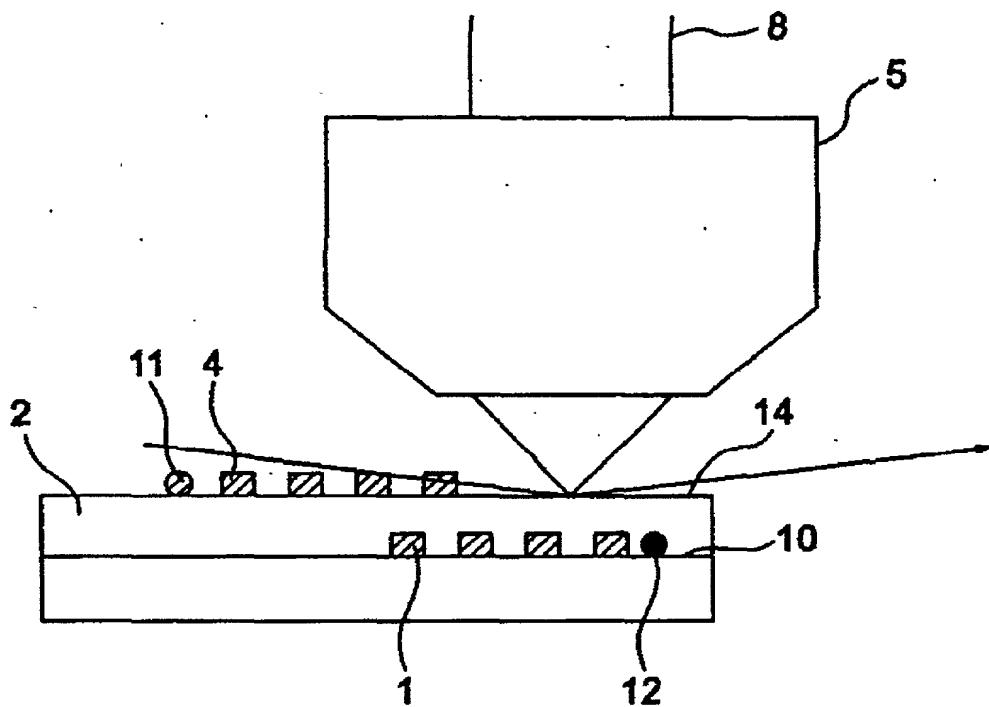
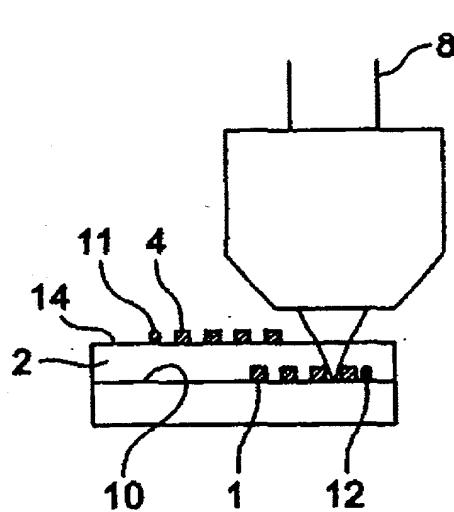


Fig. 12

(a)



(b)

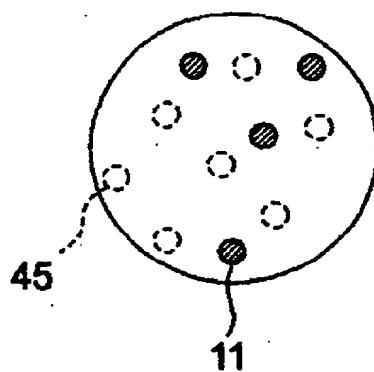
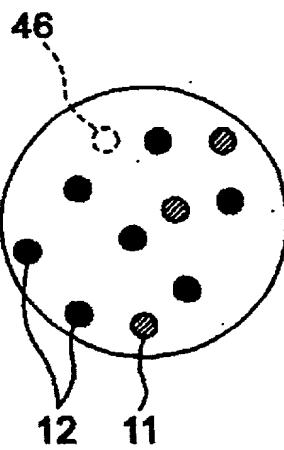
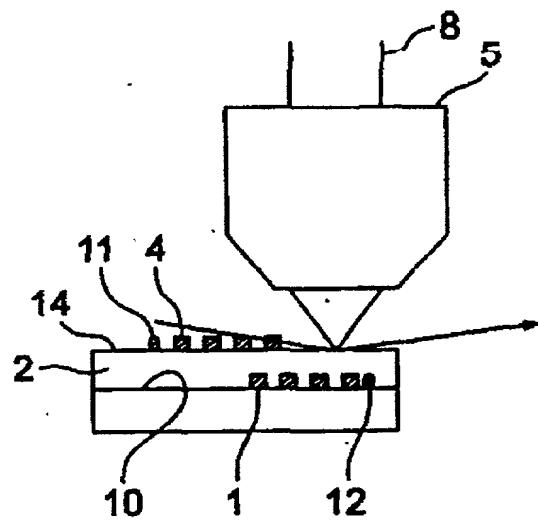


Fig. 13

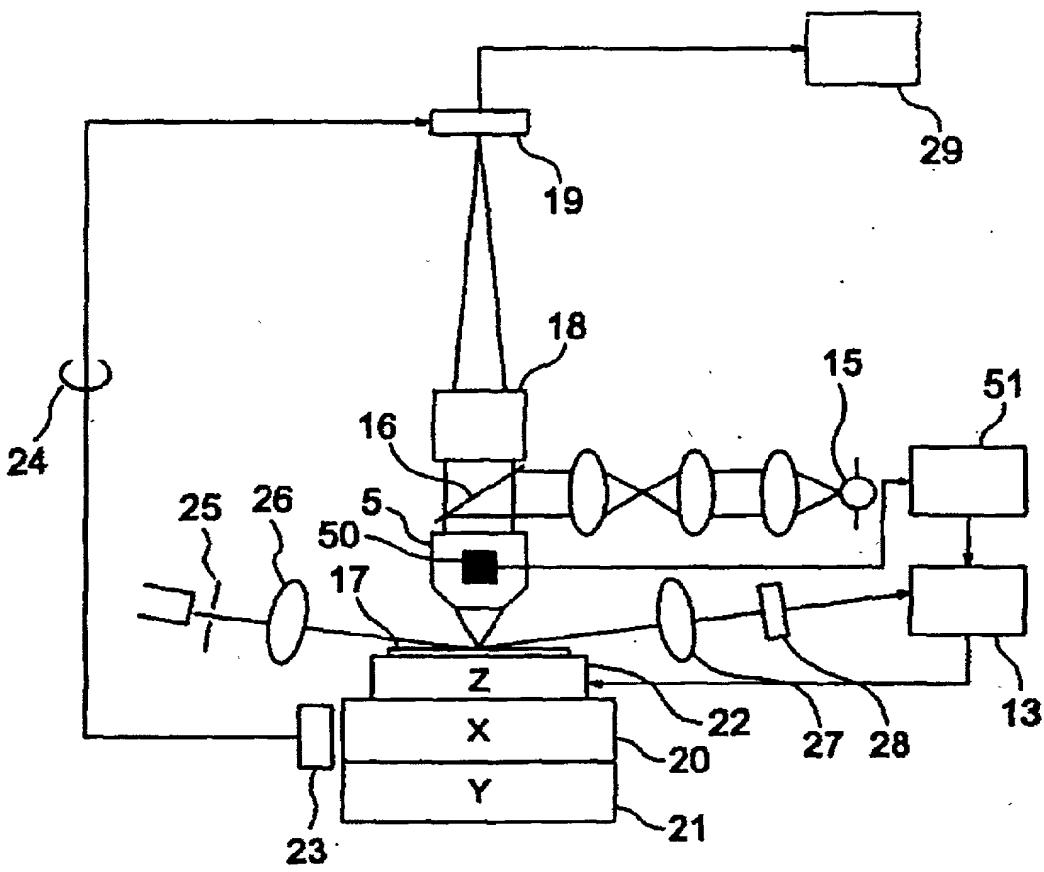


Fig. 14

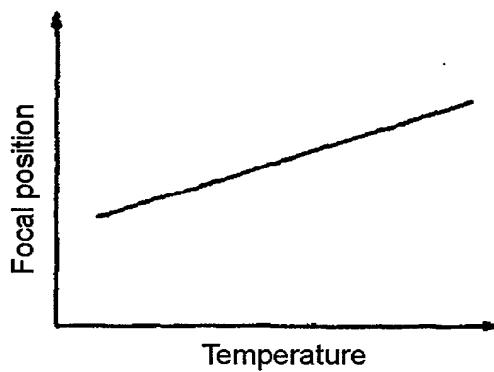


Fig. 15

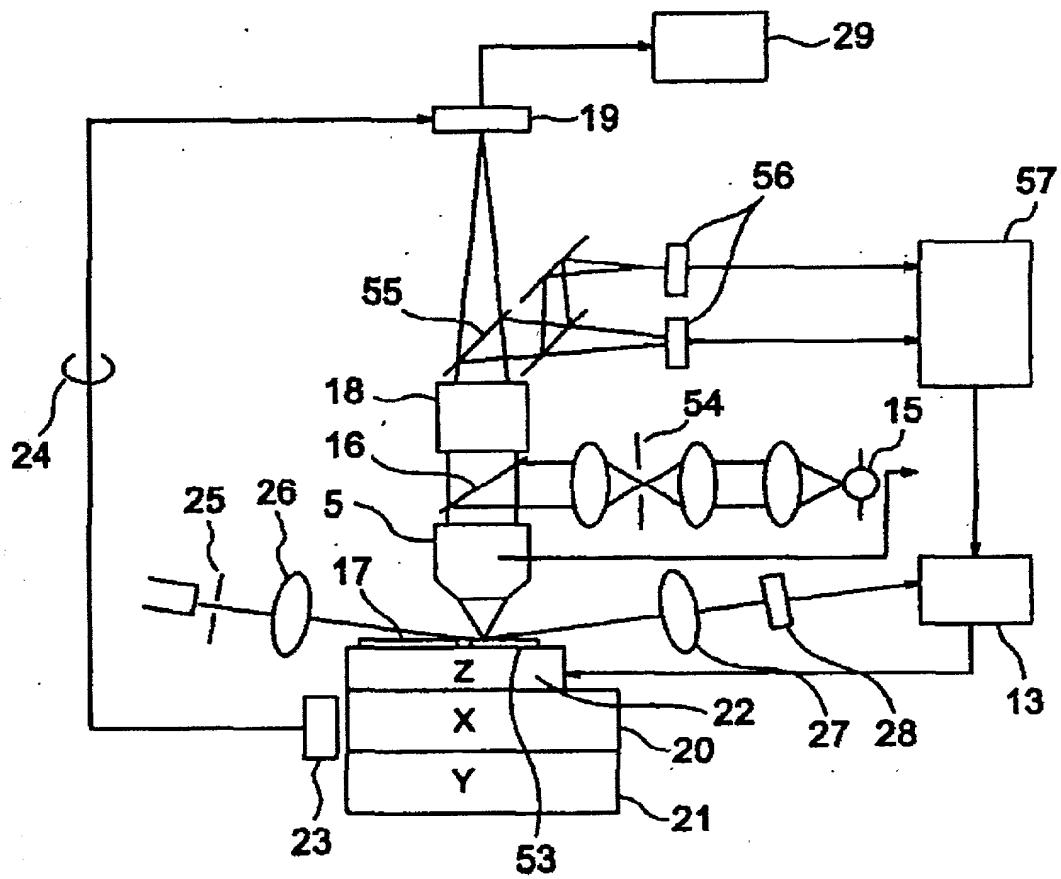


Fig. 16

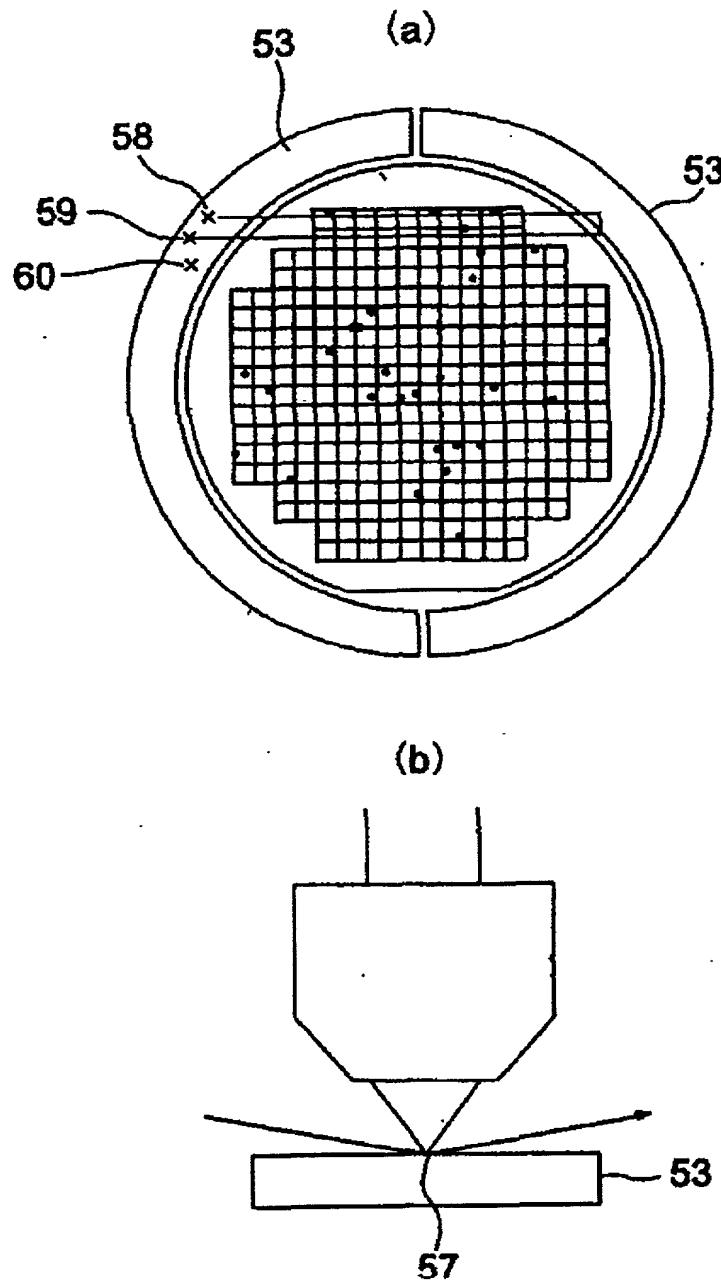


Fig. 17

